

Special Issue

Intelligent Processing on Image and Optical Information, Volume II

Message from the Guest Editor

- Intelligent image processing
- Machine and robot vision
- Optical information processing
- IR, THz, MMW, SAR image analysis
- Bio-medical image analysis
- Three-dimensional information processing
- Image detection, recognition, and tracking
- Segmentation and feature extraction
- Image registration and fusion
- Image enhancement and restoration

Guest Editor

Prof. Dr. Seokwon Yeom

School of AI, Deagu University, Gyeongsan 38453, Republic of Korea

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Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
appls@mdpi.com

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,
20133 Milano, Italy

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